

FDMS9600S-VB Datasheet Dual N-Channel 30V (D-S) MOSFET

FEAT

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}$ (Ω)	I _D (A)	Q _g (Typ.)			
30	$0.0034 \text{ at V}_{GS} = 10 \text{ V}$	60	17 nC			
	$0.0043 \text{at V}_{GS} = 4.5 \text{V}$	55	17 110			

FEATURES

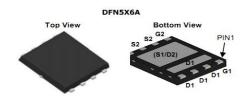
- Halogen-free According to IEC 61249-2-21 Definition
- Trench Power MOSFET
- 100 % UIS Tested
- 100 % R_q Tested
- Compliant to RoHS Directive 2002/95/EC

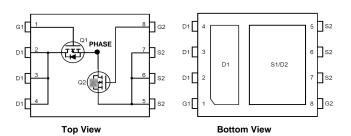


ROHS COMPLIANT HALOGEN FREE

APPLICATIONS

- Set Top Box
- Low Current DC/DC





ABSOLUTE MAXIMUM RATINGS T _A = 25 °C, unless otherwise noted					
Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V_{DS}	30	V	
Gate-Source Voltage		V_{GS}	± 20	V	
	$T_C = 25 ^{\circ}C$		60 ^a		
Continuous Drain Current (T _{.I} = 150 °C)	$T_C = 70 ^{\circ}C$	I _D	50		
Commission Plant Carron (1) = 100 C)	T _A = 25 °C	1 'D	25.2 ^{b, c}		
	T _A = 70 °C] [22.2 ^{b, c}	A	
Pulsed Drain Current		I _{DM}	200	^	
Continuous Source-Drain Diode Current	T _C = 25 °C	lo	2.25		
Continuous Source-Drain Diode Current	T _A = 25 °C	- I _S	1.48 ^{b, c}		
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	5		
Single Pulse Avalanche Energy		E _{AS}	1.25	mJ	
	T _C = 25 °C		56		
Mayimum Dawar Dissination	T _C = 70 °C	P_{D}	15	W	
Maximum Power Dissipation	T _A = 25 °C	1 'D	2.18 ^{b, c}	VV	
	T _A = 70 °C	1	1.34 ^{b, c}		
Operating Junction and Storage Temperature Range		T_J, T_{sta}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum Uni		
Maximum Junction-to-Ambient ^{a, c, d}	t ≤ 10 s	R _{thJA}	58	70	°C/W	
Maximum Junction-to-Foot (Drain)	Steady State	$R_{th,IF}$	38	45	C/ VV	

Notes:

- a. Package limited, T_C = 25 °C.
- b. Surface Mounted on 1" x 1" FR4 board.
- c. t = 10 s
- d. Maximum under Steady State conditions is 110 °C/W.



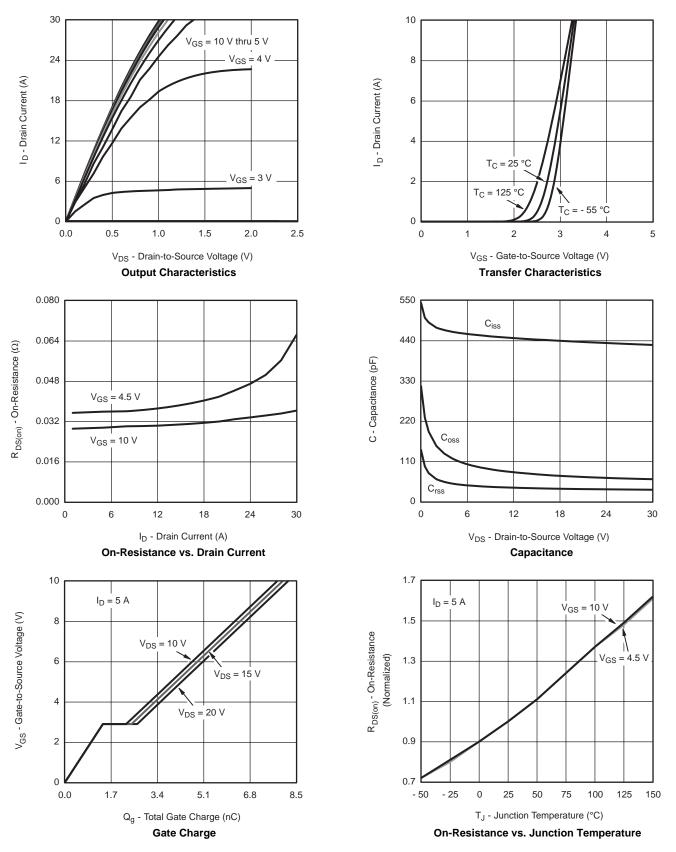
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static				<u>'</u>		•	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μA		32		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 5.0			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	1.0		2.5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$			1		
		V _{DS} = 30 V, V _{GS} = 0 V, T _J = 55 °C			10	μΑ	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	10			Α	
Drain-Source On-State Resistance ^a	` '	$V_{GS} = 10 \text{ V}, I_D = 5 \text{ A}$		0.0034		Ω	
	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_{D} = 4 \text{ A}$		0.0043			
Forward Transconductance ^a	g _{fs}	$V_{DS} = 10 \text{ V}, I_D = 5 \text{ A}$		16		S	
Dynamic ^b		-		1		<u> </u>	
Input Capacitance	C _{iss}			1300		pF	
Output Capacitance	C _{oss}	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		257			
Reverse Transfer Capacitance	C _{rss}			155			
Total Gate Charge	Q _g	$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 5 \text{ A}$		17		nC	
				3.7	5.6		
Gate-Source Charge	Q _{gs}	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 5 \text{ A}$		1.4			
Gate-Drain Charge	Q _{gd}			1.05			
Gate Resistance	R _g	f = 1 MHz	0.8	4.3	8.6	Ω	
Turn-On Delay Time	t _{d(on)}			12	24		
Rise Time	t _r	V_{DD} = 15 V, R_L = 3 Ω		55	100		
Turn-Off Delay Time	t _{d(off)}	$I_D\cong 5$ A, V_{GEN} = 4.5 V, R_g = 1 Ω		11	22		
Fall Time	t _f			8	16		
Turn-On Delay Time	t _{d(on)}			4	8	- ns -	
Rise Time	t _r	V_{DD} = 15 V, R_L = 3 Ω		9	18		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 5$ A, $V_{GEN} = 10$ V, $R_g = 1$ Ω		10	20		
Fall Time	t _f			6	12		
Drain-Source Body Diode Characteristi	cs						
Continuous Source-Drain Diode Current	I _S	$T_C = 25 ^{\circ}C$			2.25	А	
Pulse Diode Forward Current	I _{SM}				24		
Body Diode Voltage	V _{SD}	I _S = 2 A, V _{GS} = 0 V		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			11	20	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	I _F = 5 A, dI/dt = 100 A/μs, T _J = 25 °C		4	8	nC	
Reverse Recovery Fall Time	t _a	1 _F = 0 Λ, αι/αι = 100 Α/μs, 1 _J = 25 C		7		20	
Reverse Recovery Rise Time	t _b	b		4		ns	

Notes:

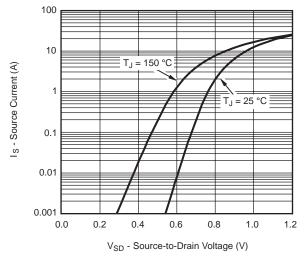
- a. Pulse test; pulse width $\leq 300~\mu s,~duty~cycle \leq 2~\%$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

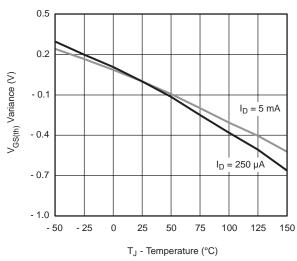




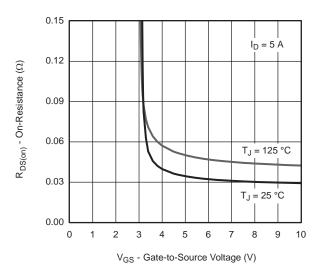




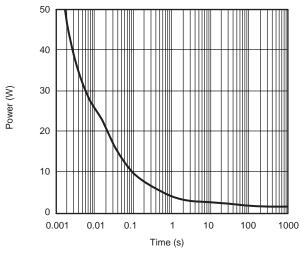
Source-Drain Diode Forward Voltage



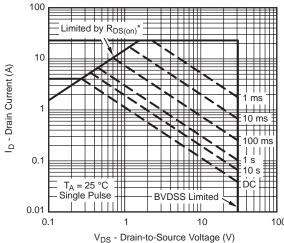
Threshold Voltage



On-Resistance vs. Gate-to-Source Voltage



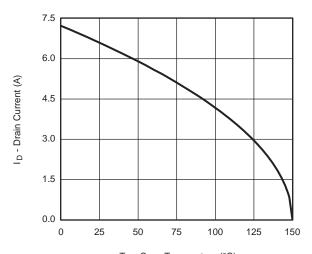
Single Pulse Power



* V_{GS} > minimum V_{GS} at which $R_{DS(on)}$ is specified

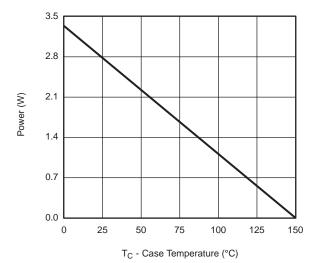
Safe Operating Area, Junction-to-Ambient



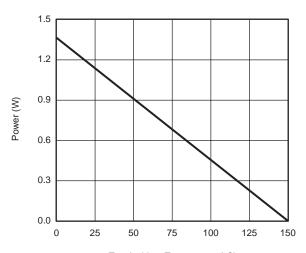


T_C - Case Temperature (°C)

Current Derating*



Power, Junction-to-Foot

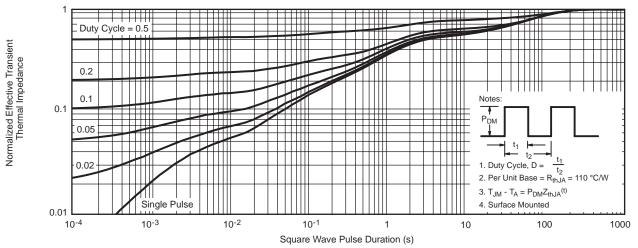


T_A - Ambient Temperature (°C)

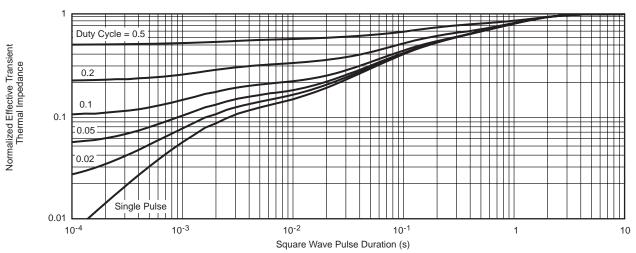
Power, Junction-to-Ambient

^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



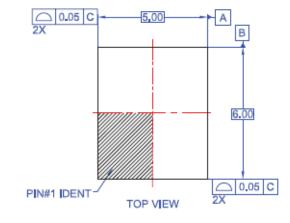


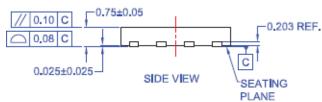
Normalized Thermal Transient Impedance, Junction-to-Ambient

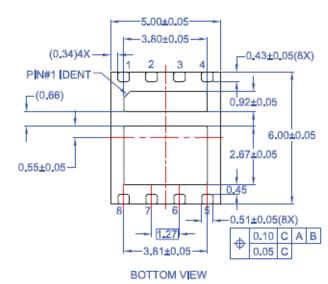


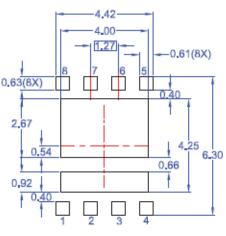
Normalized Thermal Transient Impedance, Junction-to-Foot











RECOMMENDED LAND PATTERN

NOTE:

- PACKAGE DOES NOT FULLY CONFORM TO JEDEC STANDARD.
- B. DIMENSIONS ARE IN MILLIMETERS.
- DIMENSIONS AND TOLERANCES PER ASME Y14.5M,
- LAND PATTERN RECOMMENDATION IS EXISTING INDUSTRY LAND PATTERN.
- E. DRAWING FILENAME: MKT-MLP08Krev3.



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